

| L<br>Number | Hits | Search Text   | DB  | Time stamp            |
|-------------|------|---|---|-----------------------|
| 5           | 47   | (US-6484064-\$ or US-5659467-\$ or<br>US-5655110-\$ or US-6532392-\$ or<br>US-6397114-\$ or US-6539267-\$ or<br>US-6486081-\$ or US-6017143-\$ or<br>US-5015492-\$ or US-6580960-\$ or<br>US-6509197-\$ or US-6383402-\$ or<br>US-6275740-\$ or US-6119047-\$ or<br>US-5658418-\$ or US-6524873-\$ or<br>US-6392434-\$ or US-6327555-\$ or<br>US-6314379-\$ or US-6265232-\$ or<br>US-5828778-\$ or US-6581191-\$ or<br>US-6553548-\$ or US-5625816-\$ or<br>US-6542837-\$ or US-6532182-\$).did. or<br>(US-6456951-\$ or US-6304791-\$ or<br>US-6202037-\$ or US-6184048-\$ or<br>US-6154714-\$ or US-5991699-\$ or<br>US-5923553-\$ or US-5889674-\$ or<br>US-5646870-\$ or US-5576223-\$ or<br>US-5886909-\$ or US-6587744-\$ or<br>US-6535776-\$ or US-6363294-\$ or<br>US-6161054-\$ or US-6542830-\$ or<br>US-6473665-\$ or US-5985497-\$ or<br>US-5844850-\$).did. or (US-20010020194-\$<br>or US-20020121915-\$).did.   | USPAT;<br>US-PGPUB                                      | 2003/07/18<br>16:37   |
| 10          | 6    | ((US-6484064-\$ or US-5659467-\$ or<br>US-5655110-\$ or US-6532392-\$ or<br>US-6397114-\$ or US-6539267-\$ or<br>US-6486081-\$ or US-6017143-\$ or<br>US-5015492-\$ or US-6580960-\$ or<br>US-6509197-\$ or US-6383402-\$ or<br>US-6275740-\$ or US-6119047-\$ or<br>US-5658418-\$ or US-6524873-\$ or<br>US-6392434-\$ or US-6327555-\$ or<br>US-6314379-\$ or US-6265232-\$ or<br>US-5828778-\$ or US-6581191-\$ or<br>US-6553548-\$ or US-5625816-\$ or<br>US-6542837-\$ or US-6532182-\$).did. or<br>(US-6456951-\$ or US-6304791-\$ or<br>US-6202037-\$ or US-6184048-\$ or<br>US-6154714-\$ or US-5991699-\$ or<br>US-5923553-\$ or US-5889674-\$ or<br>US-5646870-\$ or US-5576223-\$ or<br>US-5886909-\$ or US-6587744-\$ or<br>US-6535776-\$ or US-6363294-\$ or<br>US-6161054-\$ or US-6542830-\$ or<br>US-6473665-\$ or US-5985497-\$ or<br>US-5844850-\$).did. or (US-20010020194-\$<br>or US-20020121915-\$).did.) and (server\$1<br>with (database\$1 or (data adj base\$1))) | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/18<br>16:46 - |

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|----|------|--|---|---------------------|
| 11 | 7    | ((US-6484064-\$ or US-5659467-\$ or<br>US-5655110-\$ or US-6532392-\$ or<br>US-6397114-\$ or US-6539267-\$ or<br>US-6486081-\$ or US-6017143-\$ or<br>US-5015492-\$ or US-6580960-\$ or<br>US-6509197-\$ or US-6383402-\$ or<br>US-6275740-\$ or US-6119047-\$ or<br>US-5658418-\$ or US-6524873-\$ or<br>US-6392434-\$ or US-6327555-\$ or<br>US-6314379-\$ or US-6265232-\$ or<br>US-5828778-\$ or US-6581191-\$ or<br>US-6553548-\$ or US-5625816-\$ or<br>US-6542837-\$ or US-6532182-\$).did. or<br>(US-6456951-\$ or US-6304791-\$ or<br>US-6202037-\$ or US-6184048-\$ or<br>US-6154714-\$ or US-5991699-\$ or<br>US-5923553-\$ or US-5889674-\$ or<br>US-5646870-\$ or US-5576223-\$ or<br>US-5886909-\$ or US-6587744-\$ or<br>US-6535776-\$ or US-6363294-\$ or<br>US-6161054-\$ or US-6542830-\$ or<br>US-6473665-\$ or US-5985497-\$ or<br>US-5844850-\$).did. or (US-20010020194-\$<br>or US-20020121915-\$).did.) and server\$1<br>"5844850" | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/18<br>16:46 |
| 12 | 12   |  | USPAT   | 2003/07/18<br>18:39 |
| 13 | 184  | (702/81).CCLS.   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/18<br>18:52 |
| 14 | 51   | (702/83).CCLS.   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/18<br>18:52 |
| 15 | 281  | (702/84).CCLS.   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/18<br>18:52 |
| 16 | 1012 | (702/188).CCLS.  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/18<br>18:52 |
| 17 | 313  | (702/189).CCLS.  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/18<br>18:52 |
| 18 | 75   | ((702/84).CCLS.) and (cause\$2 with<br>(drift\$3 or defect\$5 or error\$1 or<br>variation\$1 or variance\$1))  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/18<br>18:53 |
| 19 | 33   | ((702/188).CCLS.) and (cause\$2 with<br>(drift\$3 or defect\$5 or error\$1 or<br>variation\$1 or variance\$1))   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/18<br>18:53 |
| 20 | 46   | ((702/189).CCLS.) and (cause\$2 with<br>(drift\$3 or defect\$5 or error\$1 or<br>variation\$1 or variance\$1))   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/18<br>18:53 |
| -  | 3425 | process with drift\$3  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/10<br>16:16 |

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|---|-------|---|---|---------------------|
| - | 187   | (process with drift\$3 with cause\$1) and (categor\$3 or feature\$1 or profile\$1)  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/10<br>16:16 |
| - | 377   | (process with drift\$3) and (cause with drift\$3)   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/10<br>16:16 |
| - | 789   | (process with drift\$3) and (cause\$1 with drift\$3)  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/10<br>17:23 |
| - | 555   | ((process with drift\$3) and (cause\$1 with drift\$3)) and (compare\$1 or comparison\$1 or comparing)   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/10<br>16:20 |
| - | 331   | ((process with drift\$3) and (cause\$1 with drift\$3)) and (compare\$1 or comparison\$1 or comparing) and (manufactur\$5 or fabricat\$6)  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/10<br>16:56 |
| - | 21    | ((process with drift\$3) and (cause\$1 with drift\$3)) and ((advanced near1 process near1 control\$1) or catalyst or (semiconductor near2 equipment near2 material\$1) or (computer near2 integrated near manufactur\$5)) | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/10<br>16:28 |
| - | 0     | 6484064.URPN.   | USPAT   | 2003/07/10<br>16:28 |
| - | 4     | ("5862055"   "6255125"   "6277658"   "6292708").PN.   | USPAT   | 2003/07/10<br>16:36 |
| - | 14059 | (advanced with micro with devices) .asn.  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/10<br>16:39 |
| - | 181   | ((advanced with micro with devices) .asn.) and drift\$3   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/16<br>14:31 |
| - | 35    | ((advanced with micro with devices) .asn.) and (drift\$3 with process\$2)   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/11<br>08:43 |
| - | 62096 | process with variation\$1   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/10<br>16:56 |
| - | 2905  | (process with variation\$1) and drift\$3  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/10<br>16:57 |
| - | 533   | ((process with variation\$1) and drift\$3) and (cause\$1 with drift\$3)   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/10<br>16:58 |
| - | 77    | ((process with variation\$1) and drift\$3) and ((cause\$1 with drift\$3) with (detect\$5 or determin\$6))   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/10<br>16:59 |

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| - | 86   | (process with drift\$3) and ((cause\$1 with drift\$3) with (detect\$5 or determin\$6))  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/11<br>08:02 |
| - | 43   | (process with drift\$3) and ((cause\$1 with variation\$3) with (detect\$5 or determin\$6))  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/11<br>08:02 |
| - | 1863 | (438/\$.ccls. or 700/\$.ccls. or 702/\$.ccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6)) and (process\$3 with (error\$1 or drift\$3))   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/11<br>08:48 |
| - | 479  | (438/\$.ccls. or 700/\$.ccls. or 702/\$.ccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6)) and (process\$3 with (error\$1 or drift\$3)) and (cause\$1 with (error\$1 or drift\$3))  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/11<br>08:49 |
| - | 82   | (438/\$.ccls. or 700/\$.ccls. or 702/\$.ccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6)) and (process\$3 with (error\$1 or drift\$3)) and (cause\$1 with (error\$1 or drift\$3) with (determin\$7 or detect\$6))  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/14<br>17:00 |
| - | 126  | (438/\$.ccls. or 700/\$.ccls. or 702/\$.ccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1)) and (process\$3 with (error\$1 or drift\$3)) and (cause\$1 with (error\$1 or drift\$3 or defect\$1) with (determin\$7 or detect\$6))  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/14<br>19:20 |
| - | 30   | (716/\$.ccls. ) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1)) and (process\$3 with (error\$1 or drift\$3)) and (cause\$1 with (error\$1 or drift\$3 or defect\$1) with (determin\$7 or detect\$6))   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/14<br>18:57 |
| - | 3    | (438/\$.ccls. or 700/\$.ccls. or 702/\$.ccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1)) and (process\$3 with (error\$1 or drift\$3)) and (cause\$1 with variance\$1 with (determin\$7 or detect\$6))  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/14<br>19:19 |
| - | 3    | (438/\$.ccls. or 700/\$.ccls. or 702/\$.ccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1)) and (process\$3 with (error\$1 or drift\$3)) and (cause\$1 with variance\$1 with (determin\$7 or detect\$6))  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/14<br>19:19 |
| - | 201  | (438/\$.ccls. or 700/\$.ccls. or 702/\$.ccls. or 7160?\$.ccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1)) and (process\$3 with (error\$1 or drift\$3 or variation\$1 or variance\$1)) and (cause\$1 with (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with (determin\$7 or detect\$6)) | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/17<br>09:42 |

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|---|------|--|---|---------------------|
| - | 58   | drift adj analy\$5   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/14<br>21:47 |
| - | 104  | (438/\$.ccls. or 700/\$.ccls. or 702/\$.ccls. or 7160?\$.ccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1)) and (process\$3 with (error\$1 or drift\$3 or variation\$1 or variance\$1)) and (cause\$1 with (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with (determin\$7 or detect\$6)) and (batch\$2 or lot\$1) | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/17<br>09:41 |
| - | 117  | (438/\$.ccls. or 700/\$.ccls. or 702/\$.ccls. or 7160?\$.ccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1)) and (process\$3 with (error\$1 or drift\$3 or variation\$1 or variance\$1)) and (cause\$1 with (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with (determin\$7 or detect\$6)) and yield\$1             | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/17<br>09:41 |
| - | 4001 | characterist\$6 with thread\$1   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/15<br>10:37 |
| - | 1073 | characterist\$6 near2 thread\$1  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/15<br>10:38 |
| - | 519  | (characterist\$6 near2 thread\$1) and (manufactur\$6 or fabricat\$6)   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/15<br>10:38 |
| - | 358  | (characterist\$6 near2 thread\$1) and (manufactur\$6 or fabricat\$6) and process\$3  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/15<br>10:39 |
| - | 111  | (characterist\$6 near2 thread\$1) and (manufactur\$6 or fabricat\$6) and process\$3 and (drift\$3 or variance\$1 or error or defect\$1 )   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/15<br>10:43 |
| - | 28   | (characterist\$6 near2 thread\$1) and (manufactur\$6 or fabricat\$6) and process\$3 and (drift\$3 or variance\$1 )   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/15<br>10:46 |
| - | 4    | (characterist\$6 near2 thread\$1) and ((manufactur\$6 or fabricat\$6) with (wafer\$1 or semiconductor\$1 or chip\$1)) and process\$3 and (drift\$3 or variance\$1 or error or defect\$1 )  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/15<br>10:45 |
| - | 5    | (characterist\$6 near2 thread\$1) and ((manufactur\$6 or fabricat\$6) with (wafer\$1 or semiconductor\$1 or chip\$1)) and process\$3 and (drift\$3 or variance\$1 or error or defect\$1 or variation\$1 )  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/15<br>10:45 |
| - | 73   | (characterist\$6 near2 thread\$1) and (process\$3 with (drift\$3 or variance\$1 or error\$1 or variation\$1) )   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/15<br>10:47 |

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|---|----|---|---|---------------------|
| - | 86 | (characterist\$6 near2 thread\$1) and<br>(process\$3 with (drift\$3 or variance\$1 or<br>error\$1 or variation\$1 or defect\$1) )   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM TDB | 2003/07/15<br>10:47 |
| - | 3  | "6438438"   | USPÄT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM TDB | 2003/07/15<br>19:41 |
| - | 3  | "6393602"   | USPÄT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM TDB | 2003/07/15<br>19:42 |
| - | 2  | "6180424"   | USPÄT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM TDB | 2003/07/15<br>19:42 |
| - | 37 | (US-6484064-\$ or US-5659467-\$ or<br>US-5655110-\$ or US-6532392-\$ or<br>US-6397114-\$ or US-6539267-\$ or<br>US-6486081-\$ or US-6017143-\$ or<br>US-5015492-\$ or US-6580960-\$ or<br>US-6509197-\$ or US-6383402-\$ or<br>US-6275740-\$ or US-6119047-\$ or<br>US-5658418-\$ or US-6524873-\$ or<br>US-6392434-\$ or US-6327555-\$ or<br>US-6314379-\$ or US-6265232-\$ or<br>US-5828778-\$ or US-6581191-\$ or<br>US-6553548-\$ or US-5625816-\$ or<br>US-6542837-\$ or US-6532182-\$).did. or<br>(US-6456951-\$ or US-6304791-\$ or<br>US-6202037-\$ or US-6184048-\$ or<br>US-6154714-\$ or US-5991699-\$ or<br>US-5923553-\$ or US-5889674-\$ or<br>US-5646870-\$ or US-5576223-\$).did. or<br>(US-20010020194-\$).did.                  | USPÄT;<br>US-PGPUB                                      | 2003/07/16<br>13:00 |
| - | 28 | ((US-6484064-\$ or US-5659467-\$ or<br>US-5655110-\$ or US-6532392-\$ or<br>US-6397114-\$ or US-6539267-\$ or<br>US-6486081-\$ or US-6017143-\$ or<br>US-5015492-\$ or US-6580960-\$ or<br>US-6509197-\$ or US-6383402-\$ or<br>US-6275740-\$ or US-6119047-\$ or<br>US-5658418-\$ or US-6524873-\$ or<br>US-6392434-\$ or US-6327555-\$ or<br>US-6314379-\$ or US-6265232-\$ or<br>US-5828778-\$ or US-6581191-\$ or<br>US-6553548-\$ or US-5625816-\$ or<br>US-6542837-\$ or US-6532182-\$).did. or<br>(US-6456951-\$ or US-6304791-\$ or<br>US-6202037-\$ or US-6184048-\$ or<br>US-6154714-\$ or US-5991699-\$ or<br>US-5923553-\$ or US-5889674-\$ or<br>US-5646870-\$ or US-5576223-\$).did. or<br>(US-20010020194-\$).did.) and identif\$5 | USPAT   | 2003/07/16<br>13:00 |

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|---|------|---|---|---------------------|
| - | 29   | ((US-6484064-\$ or US-5659467-\$ or<br>US-5655110-\$ or US-6532392-\$ or<br>US-6397114-\$ or US-6539267-\$ or<br>US-6486081-\$ or US-6017143-\$ or<br>US-5015492-\$ or US-6580960-\$ or<br>US-6509197-\$ or US-6383402-\$ or<br>US-6275740-\$ or US-6119047-\$ or<br>US-5658418-\$ or US-6524873-\$ or<br>US-6392434-\$ or US-6327555-\$ or<br>US-6314379-\$ or US-6265232-\$ or<br>US-5828778-\$ or US-6581191-\$ or<br>US-6553548-\$ or US-5625816-\$ or<br>US-6542837-\$ or US-6532182-\$).did. or<br>(US-6456951-\$ or US-6304791-\$ or<br>US-6202037-\$ or US-6184048-\$ or<br>US-6154714-\$ or US-5991699-\$ or<br>US-5923553-\$ or US-5889674-\$ or<br>US-5646870-\$ or US-5576223-\$).did. or<br>(US-20010020194-\$).did.) and identif\$5<br>((advanced with micro with devices)<br>.asn.) and drift\$3 and identifier\$1 | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/16<br>13:00 |
| - | 14   | ((advanced with micro with devices)<br>.asn.) and drift\$3 and identifier\$1  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/16<br>14:33 |
| - | 2    | ((advanced with micro with devices)<br>.asn.) and drift\$3 and thread\$1  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/16<br>14:34 |
| - | 852  | ((advanced with micro with devices)<br>.asn.) and (cause\$2 with (drift\$3 or<br>defect\$5 or error\$1 or variation\$1 or<br>variance\$1))  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/16<br>14:35 |
| - | 129  | ((advanced with micro with devices)<br>.asn.) and (cause\$2 with (drift\$3 or<br>defect\$5 or error\$1 or variation\$1 or<br>variance\$1) with (determin\$6 or<br>detect\$7))   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/16<br>17:27 |
| - | 216  | (700/110).CCLS.   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/16<br>17:28 |
| - | 750  | (700/121).CCLS.   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/16<br>19:32 |
| - | 153  | (process\$1 with drift\$1)and (cause\$2 with<br>(drift\$3 or defect\$5 or error\$1 or<br>variation\$1 or variance\$1) with<br>(determin\$6 or detect\$7))   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/18<br>18:53 |
| - | 1813 | (process\$1 with (variance\$1 or<br>variation\$1))and (cause\$2 with (drift\$3<br>or defect\$5 or error\$1 or variation\$1 or<br>variance\$1) with (determin\$6 or<br>detect\$7))   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/16<br>18:02 |
| - | 2    | ("5624590"   "5848842").PN.   | USPAT   | 2003/07/16<br>18:03 |
| - | 1    | 6268270.URPN.   | USPAT   | 2003/07/16<br>18:03 |
| - | 307  | (700/108).CCLS.   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/16<br>19:32 |

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| - | 843 | (700/117).CCLS.  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/16<br>19:32 |
| - | 150 | (700/109).CCLS.  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/16<br>20:23 |
| - | 40  | ((700/121).CCLS.) and drift\$3   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/16<br>20:33 |
| - | 13  | ((700/121).CCLS.) and drift\$3 and<br>(cause\$1 with (variance\$1 or variation\$1<br>or drift\$1))   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/16<br>20:43 |
| - | 167 | ((700/121).CCLS.) and process\$3 and<br>(cause\$1 with (variance\$1 or variation\$1<br>or drift\$1 or error or defect\$1))   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/16<br>20:50 |
| - | 22  | ((700/121).CCLS.) and drift\$3 and<br>(cause\$1 with (variance\$1 or variation\$1<br>or drift\$1 or error or defect\$1))   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/16<br>20:44 |
| - | 53  | ((700/121).CCLS.) and process\$3 and<br>(cause\$1 with (variance\$1 or variation\$1<br>or drift\$1 or error or defect\$1) with<br>(determin\$7 or detect\$6))  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/16<br>20:53 |
| - | 53  | ((700/121).CCLS.) and (cause\$1 with<br>(variance\$1 or variation\$1 or drift\$1 or<br>error or defect\$1) with (determin\$7 or<br>detect\$6))   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/17<br>10:41 |
| - | 112 | (438/\$.ccls. or 700/\$.ccls. or<br>702/\$.ccls. or 716/\$.ccls.) and ((wafer\$1<br>or semiconductor\$1 or chip\$1) with<br>(manufactur\$5 or fabricati\$5 or produc\$6<br>or defect\$1)) and (process\$3 with<br>(error\$1 or drift\$3 or variation\$1 or<br>variance\$1)) and (cause\$1 with (error\$1<br>or drift\$3 or defect\$1 or variance\$1 or<br>variation\$1) with (determin\$7 or<br>detect\$6)) and (batch\$2 or lot\$1) | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/17<br>09:42 |
| - | 132 | (438/\$.ccls. or 700/\$.ccls. or<br>702/\$.ccls. or 716/\$.ccls.) and ((wafer\$1<br>or semiconductor\$1 or chip\$1) with<br>(manufactur\$5 or fabricati\$5 or produc\$6<br>or defect\$1)) and (process\$3 with<br>(error\$1 or drift\$3 or variation\$1 or<br>variance\$1)) and (cause\$1 with (error\$1<br>or drift\$3 or defect\$1 or variance\$1 or<br>variation\$1) with (determin\$7 or<br>detect\$6)) and yield\$1             | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/17<br>09:43 |
| - | 235 | (438/\$.ccls. or 700/\$.ccls. or<br>702/\$.ccls. or 716/\$.ccls.) and ((wafer\$1<br>or semiconductor\$1 or chip\$1) with<br>(manufactur\$5 or fabricati\$5 or produc\$6<br>or defect\$1)) and (process\$3 with<br>(error\$1 or drift\$3 or variation\$1 or<br>variance\$1)) and (cause\$1 with (error\$1<br>or drift\$3 or defect\$1 or variance\$1 or<br>variation\$1) with (determin\$7 or<br>detect\$6))                          | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/17<br>15:28 |



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|---|------|---|---|---------------------|
| - | 18   | (438/\$.ccls. or 700/\$.ccls. or 702/\$.ccls. or 716/\$.ccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1)) and (process\$3 with (error\$1 or drift\$3 or variation\$1 or variance\$1)) and (cause\$1 with (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with (determin\$7 or detect\$6) with compar\$6)   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/17<br>10:32 |
| - | 6    | (438/\$.ccls. or 700/\$.ccls. or 702/\$.ccls. or 716/\$.ccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1)) and (process\$3 with (error\$1 or drift\$3 or variation\$1 or variance\$1)) and (cause\$1 with (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with identif\$9 with compar\$6)   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/17<br>10:34 |
| - | 7    | ((700/121).CCLS.) and (caus\$4 with (variance\$1 or variation\$1 or drift\$1 or error or defect\$1) with (determin\$7 or detect\$6 or identif\$9) with compar\$6)   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/17<br>10:43 |
| - | 7    | ((700/121).CCLS.) and (caus\$4 with (variance\$1 or variation\$1 or drift\$1 or error\$1 or defect\$1) with (determin\$7 or detect\$6 or identif\$9) with compar\$6)  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/17<br>10:43 |
| - | 2952 | (process\$3 with (error\$1 or drift\$3 or variation\$1 or variance\$1)) and (cause\$1 with (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with (determin\$7 or detect\$6 or identif\$8)) and ( (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with identif\$8)  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/17<br>15:31 |
| - | 230  | (process\$3 with (error\$1 or drift\$3 or variation\$1 or variance\$1)) and (cause\$1 with (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with (determin\$7 or detect\$6 or identif\$8)) and ( (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with identif\$8) and (compar\$7 with characteristic\$1)   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/17<br>15:32 |
| - | 59   | (process\$3 with (error\$1 or drift\$3 or variation\$1 or variance\$1)) and (cause\$1 with (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with (determin\$7 or detect\$6 or identif\$8)) and ( (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with identif\$8) and (compar\$7 with characteristic\$1) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1))                  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/17<br>16:02 |
| - | 7    | (process\$3 with (error\$1 or drift\$3 or variation\$1 or variance\$1)) and ((cause\$1 with (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with (determin\$7 or detect\$6 or identif\$8)) with compar\$6) and ( (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with identif\$8) and (compar\$7 with characteristic\$1) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1)) | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/17<br>16:04 |

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|---|----|--|---|---------------------|
| - | 10 | (process\$3 with (error\$1 or drift\$3 or variation\$1 or variance\$1)) and ((cause\$1 with (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with (determin\$7 or detect\$6 or identif\$8)) with compar\$6) and identif\$8 and (compar\$7 with characteristic\$1) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1)) | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/17<br>16:05 |
| - | 65 | (process\$3 with (error\$1 or drift\$3 or variation\$1 or variance\$1)) and ((cause\$1 with (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with (determin\$7 or detect\$6 or identif\$8)) with compar\$6) and identif\$8 and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1))  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/07/17<br>16:06 |